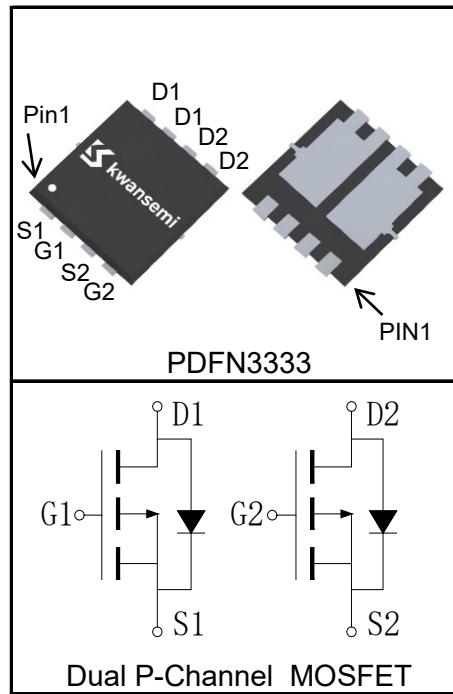


Features

- -20V/-26A,
- $R_{DS(ON)} = 16\text{m}\Omega(\text{Typ.}) @ V_{GS} = -4.5\text{V}$
- $R_{DS(ON)} = 20\text{m}\Omega(\text{Typ.}) @ V_{GS} = -2.5\text{V}$
- Low $R_{DS(ON)}$
- Super High Dense Cell Design
- Fast Switching Speed
- 100% Avalanche Tested

Pin Description



Applications

- Load Switch
- DC-DC Converter
- Power Management



Halogen-Free

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
Common Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)			
V_{DSS}	Drain-Source Voltage	-20	V
V_{GSS}	Gate-Source Voltage	± 12	
T_{Jmax}	Maximum Junction Temperature	150	$^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C = 25^\circ\text{C}$	-26
Mounted on Large Heat Sink			
$I_{DP}^{(1)}$	Pulse Drain Current	$T_C = 25^\circ\text{C}$	-104
$I_D^{(2)}$	Continuous Drain Current@ $T_C(V_{GS} = -4.5\text{V})$	$T_C = 25^\circ\text{C}$	-26
		$T_C = 100^\circ\text{C}$	-16
P_D	Continuous Drain Current@ $T_A(V_{GS} = -4.5\text{V})^{(3)}$	$T_A = 25^\circ\text{C}$	-11
		$T_A = 70^\circ\text{C}$	-9
	Maximum Power Dissipation@ T_C	$T_C = 25^\circ\text{C}$	19
		$T_C = 100^\circ\text{C}$	8
	Maximum Power Dissipation@ $T_A^{(3)}$	$T_A = 25^\circ\text{C}$	3.5
		$T_A = 70^\circ\text{C}$	2.3

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	6.4	°C/W
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	45	°C/W
Drain-Source Avalanche Ratings			
$E_{AS}^{(4)}$	Avalanche Energy, Single Pulsed	81	mJ

Electrical Characteristics ($T_C=25^\circ C$ Unless Otherwise Noted)

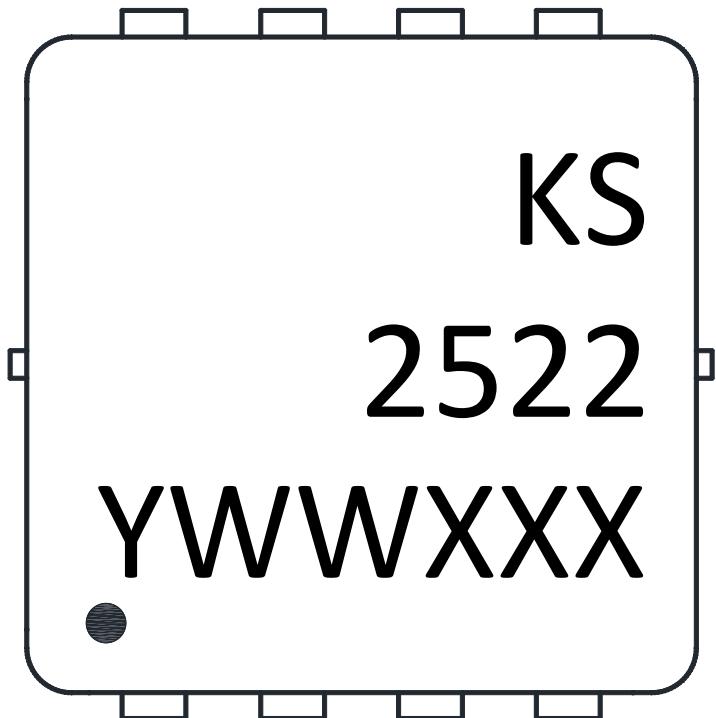
Symbol	Parameter	Test Condition	KS2522MA			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250\mu A$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20V, V_{GS}=0V$			-1	μA
		$T_J=125^\circ C$			-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-0.4	-0.65	-1	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$			± 100	nA
$R_{DS(ON)}^{(5)}$	Drain-Source On-state Resistance	$V_{GS}=-4.5V, I_{DS}=-4A$		16	20	$m\Omega$
		$V_{GS}=-2.5V, I_{DS}=-3A$		20	26	$m\Omega$
Diode Characteristics						
$V_{SD}^{(5)}$	Diode Forward Voltage	$I_{SD}=-4A, V_{GS}=0V$		-0.82	-1.2	V
t_{rr}	Reverse Recovery Time	$I_{SD}=-4A, dI_{SD}/dt=100A/\mu s$		12		ns
Q_{rr}	Reverse Recovery Charge			23		nC
Dynamic Characteristics ⁽⁶⁾						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$		7.5		Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=-10V,$ Frequency=1.0MHz		1830		pF
C_{oss}	Output Capacitance			230		
C_{rss}	Reverse Transfer Capacitance			205		
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-10V, I_{DS}=-4A,$ $V_{GS}=-4.5V, R_G=6\Omega$		15		ns
t_r	Turn-on Rise Time			28		
$t_{d(OFF)}$	Turn-off Delay Time			39		
t_f	Turn-off Fall Time			27		
Gate Charge Characteristics ⁽⁶⁾						
Q_g	Total Gate Charge	$V_{DS}=-10V, V_{GS}=-4.5V,$ $I_{DS}=-4A$		19		nC
Q_{gs}	Gate-Source Charge			4.5		
Q_{gd}	Gate-Drain Charge			6		

Notes:

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$.
- ④Limited by T_{Jmax} , Starting $T_J = 25^\circ\text{C}$, $I_{ASmax} = -18\text{A}$, $L=0.5\text{mH}$, $V_{DD} = -15\text{V}$, $R_G = 25\Omega$, $V_{GS} = -4.5\text{V}$.Part not recommended for use above this value.100% Final Test at $I_{AS} = -9\text{A}$, $L=0.5\text{mH}$.
- ⑤Pulse test;Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- ⑥Guaranteed by design, not subject to production testing.

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS2522MA	PDFN3333	Tape&Reel	5000	13"	12mm

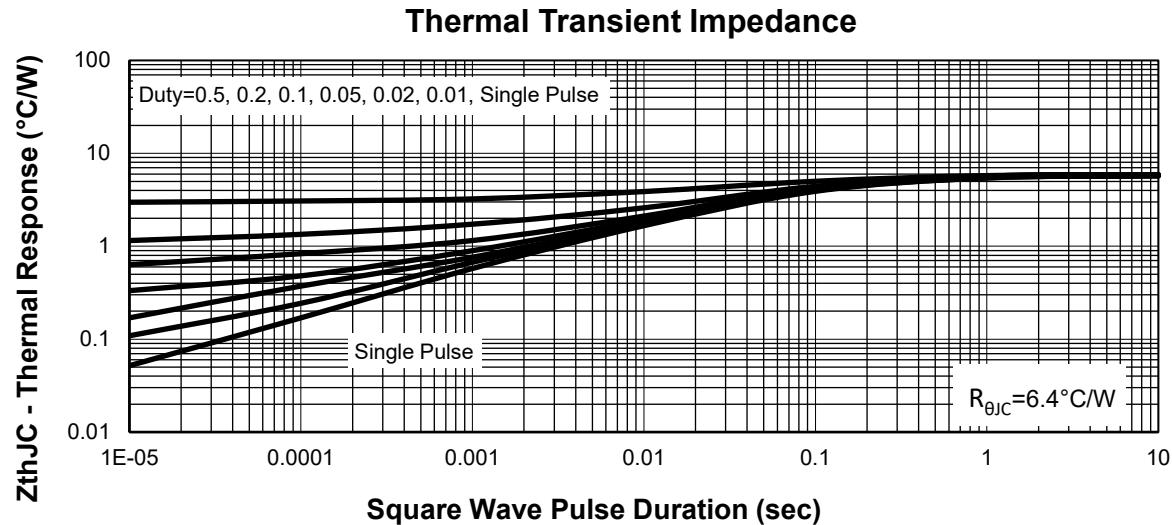
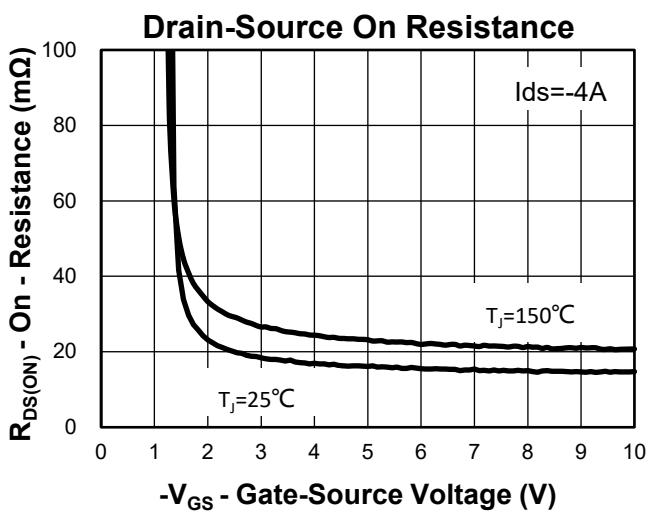
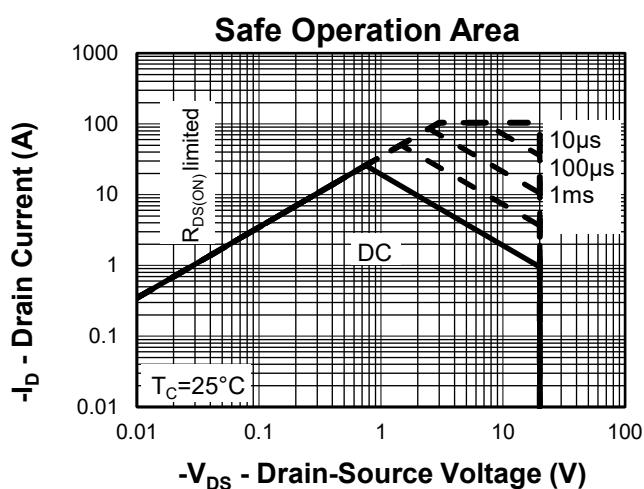
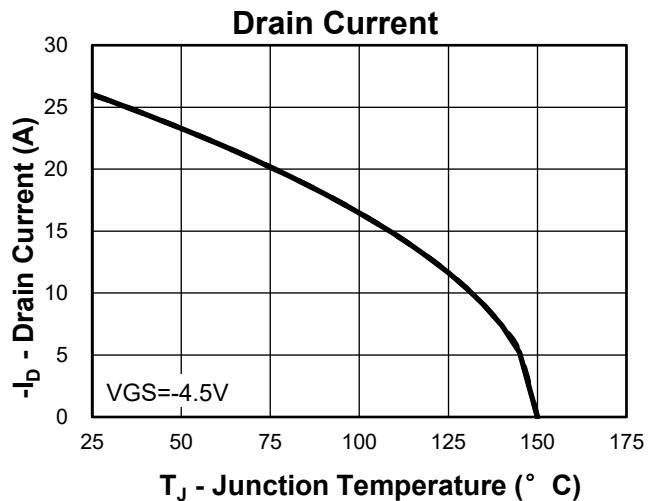
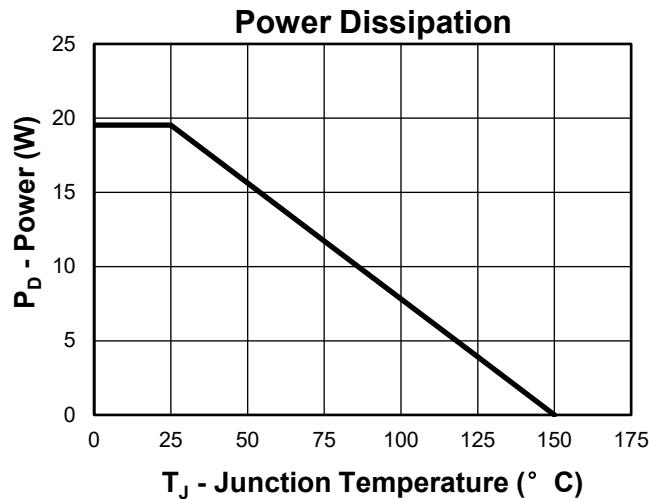


1st Line: Kwansemi Code(KS)

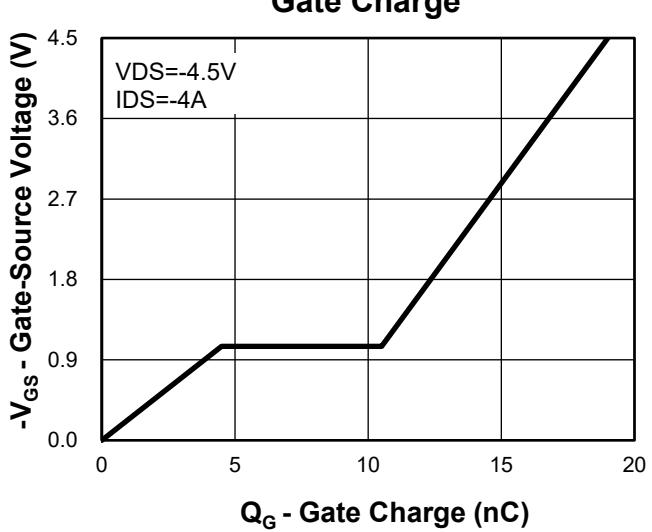
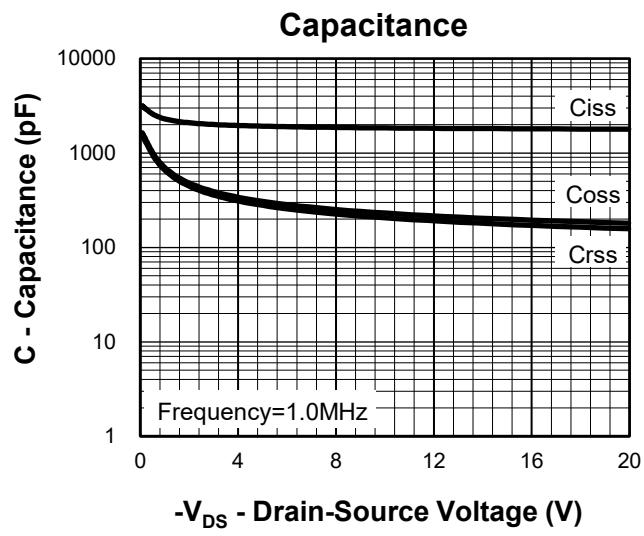
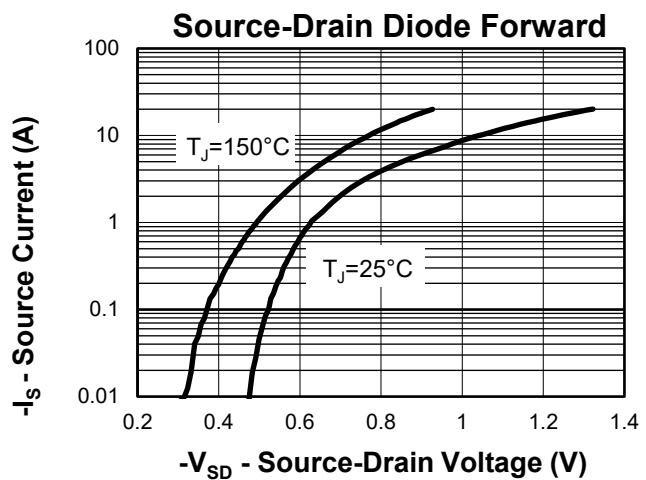
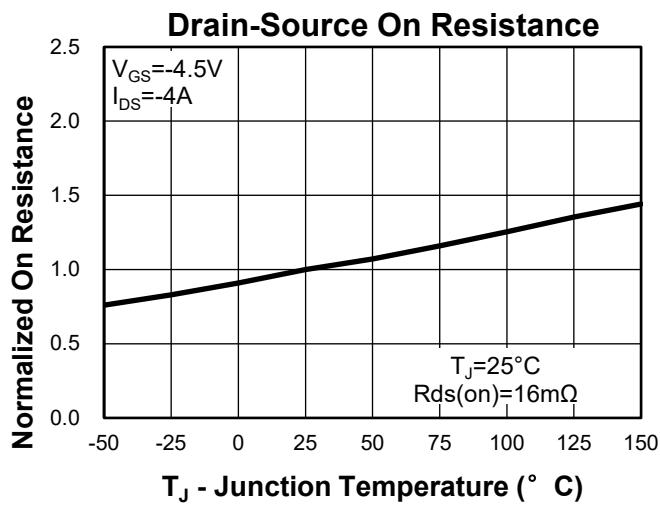
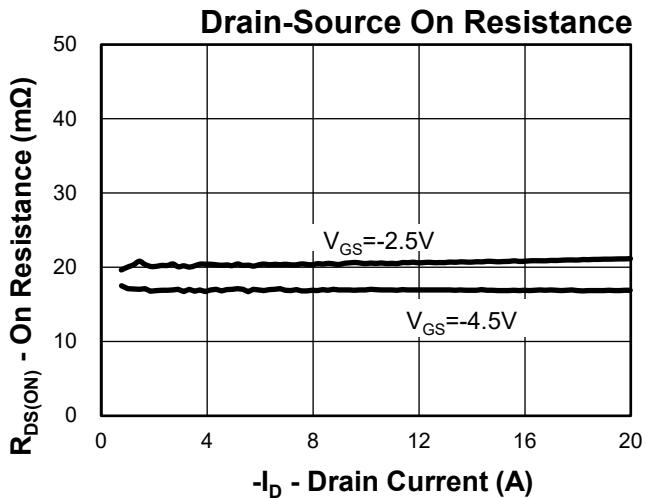
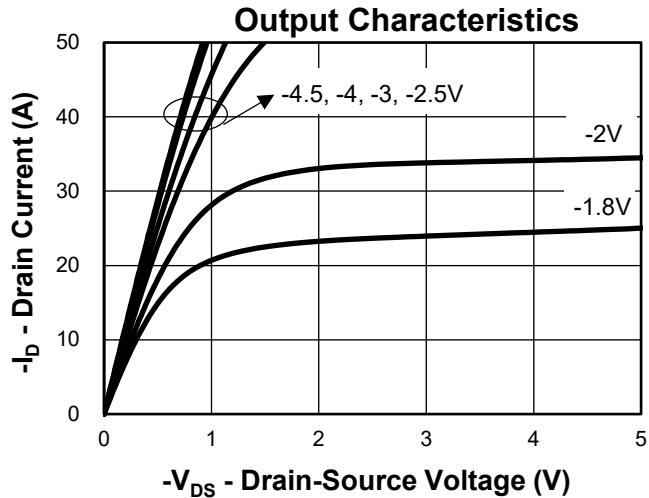
2nd Line: Part Number(2522)

3rd Line: Lot Number(YWWXXX)

Typical Characteristics

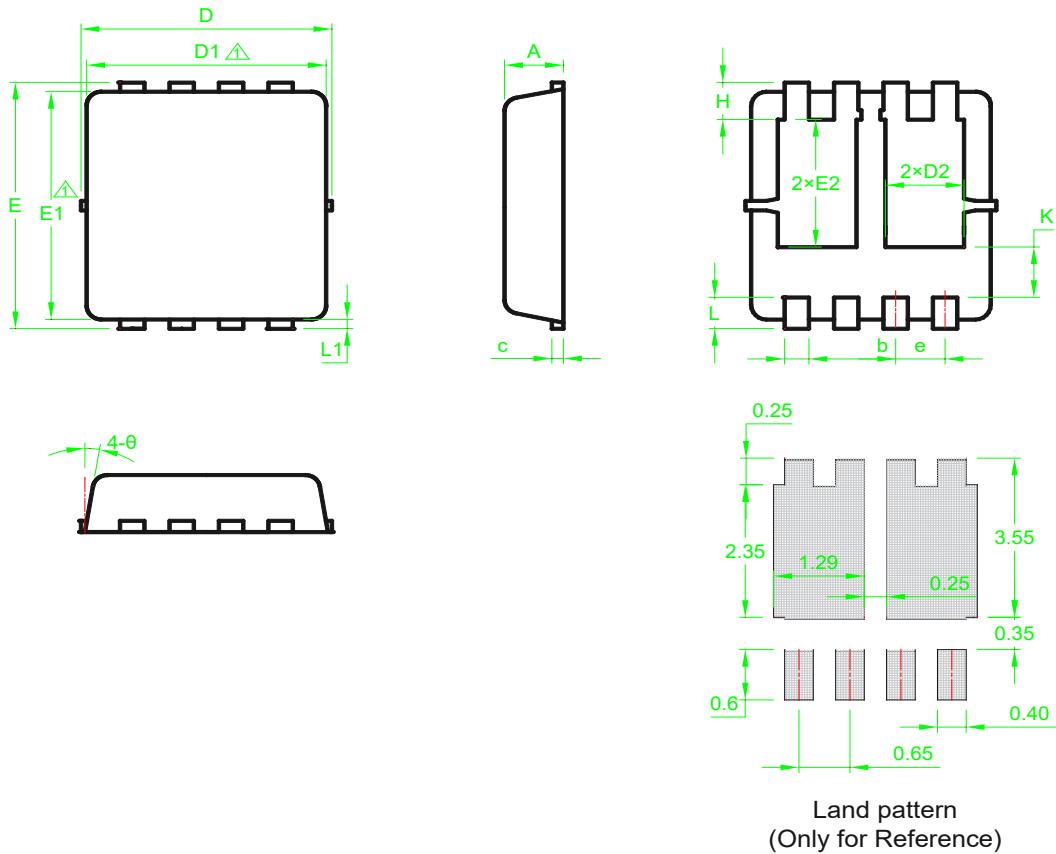


Typical Characteristics



Package Information

PDFN3333 DP1

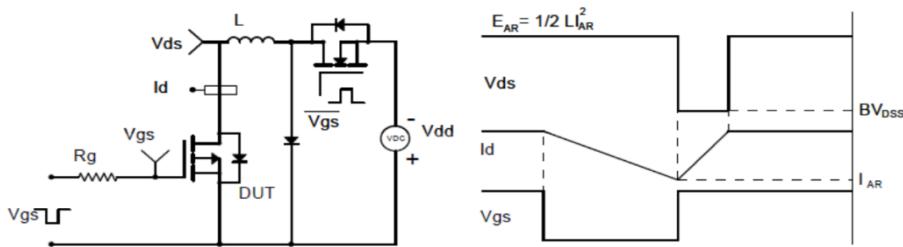


Land pattern
(Only for Reference)

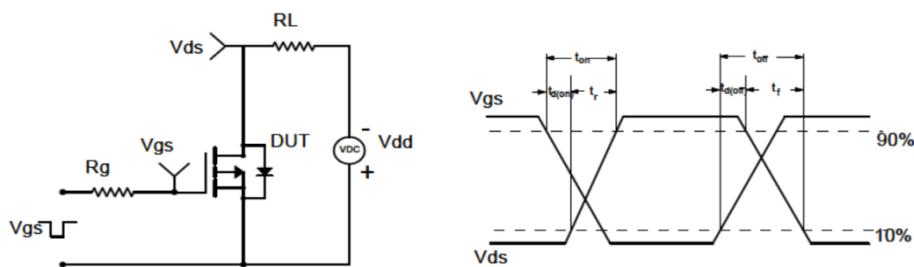
SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.80	0.90	0.028	0.031	0.035	E2	1.65	*	1.95	0.065	*	0.077
b	0.25	0.30	0.35	0.010	0.012	0.014	e	0.65BSC			0.026BSC		
c	0.10	0.15	0.25	0.004	0.006	0.010	H	0.30	0.40	0.50	0.012	0.016	0.020
D	3.20	3.30	3.40	0.126	0.130	0.134	K	0.50	*	0.80	0.020	*	0.031
D1	3.00	3.15	3.25	0.118	0.124	0.128	L	0.30	0.40	0.50	0.012	0.016	0.020
D2	0.80	1.00	1.20	0.031	0.039	0.047	L1	0.10	0.15	0.20	0.004	0.006	0.008
E	3.20	3.30	3.40	0.126	0.130	0.134	θ	8°	*	12°	8°	*	12°
E1	2.90	3.05	3.20	0.114	0.120	0.126							

 Dimensions D1 and E1 do not include mold flash protrusions or gate burrs.

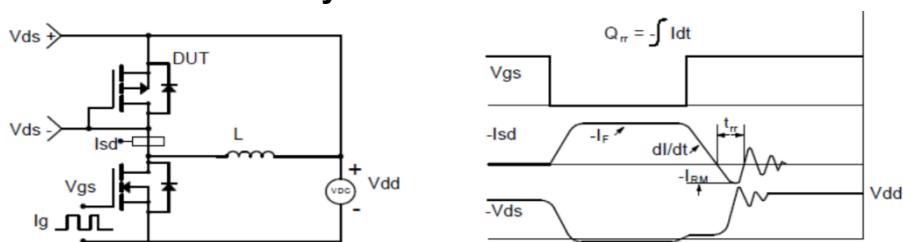
Avalanche Test Circuit and Waveforms



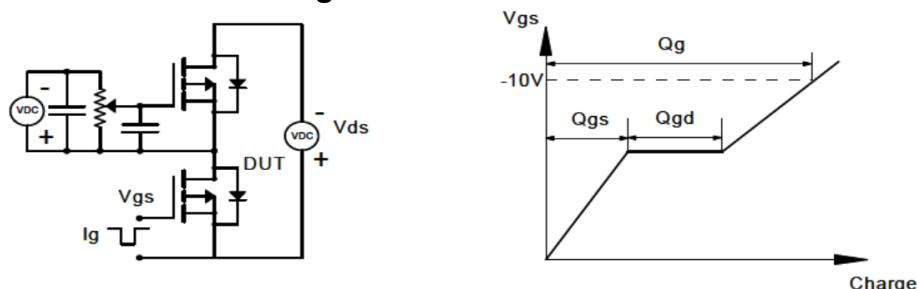
Switching Time Test Circuit and Waveforms



Diode Recovery Test Circuit and Waveforms



Gate Charge Test Circuit and Waveform



Customer Service

Kwansemi Semiconductor Co.,Ltd

Email:Sales@kwansemi.com

Web:www.kwansemi.com

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